

SUBSTITUTE FORM PTO-1449
(MODIFIED)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
06501/024001SERIAL NO.
09/202,464INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Use several sheets if necessary)APPLICANT
Kohsuke KinoFILING DATE
12/14/98

GROUP

1644

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
PNA	AD	WO 93/19178	9/30/1993	PCT				
↓	AE	JP A Hei 8-47392	2/20/1996	Japan				
↓	AF	EP 0 655 500	5/31/1995	Europe				
	AG							

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

PNA	AH	Ide et al., Allergy no Rinshou 11(3):174-178, 1991.
	AI	Taniai et al., "Epitopes on Cry j I and Cry j II for the Human IgE Antibodies Cross-Reactive . . . Pollen," Molecular Immunology 30(2):183-189, 1993.
	AJ	Okano et al., Allergy 43(9):1179-1184, 1994.
	AK	Saito et al., Chiryo 78(2):1571-1576, 1996.
	AL	Swoboda et al., "Isoforms of Bet v 1, the Major Birch Pollen Allergen, Analyzed by Liquid Chromatography, Mass Spectrometry, and cDNA Cloning," The Journal of Biological Chemistry 270(6):2607-2613, 1995.
	AM	Ikagawa et al., "Allergens, IgE, mediators, inflammatory mechanisms . . . " J Allergy Clin Immunol 97:53-64, 1996.
↓	AN	Matsushita et al., "Allele Specificity of Structural Requirement for Peptides . . . Syndrome," J. Exp. Med. 180:873-883, 1994.

EXAMINER

DATE CONSIDERED

11/19/01

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SUBSTITUTE FORM PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 06501/024001		SERIAL NO. 09/202,464		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary) (37 CFR 1.98(b))				APPLICANT Kohsuke Kino et al.		FILING DATE December 14, 1998		
				GROUP 1644				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION								
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
pat	AL	WO 94/01560	01/20/94	PCT				
↓	AM	JP 8-502163 ✓	03/12/96	Japan (w/Abstract)				
↓	AN	JP 8-176192 /	07/09/96	Japan (w/Abstract)				
	AO							
	AP							
OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)								
	AQ							
	AR							
	AS							
EXAMINER				DATE CONSIDERED				
phy N. Siga				11/28/01				
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